

4-Mbit (256K words × 16 bit) Static RAM with PowerSnooze™ and Error Correcting Code (ECC)

Features

- High speed
 - \square Access time (t_{AA}) = 10 ns / 15 ns
- Ultra-low power Deep-Sleep (DS) current
 □ I_{DS} = 15 µA
- Low active and standby currents
 - □ Active Current I_{CC} = 38-mA typical
 - ☐ Standby Current I_{SB2} = 6-mA typical
- Wide operating voltage range: 1.65 V to 2.2 V, 2.2 V to 3.6 V, 4.5 V to 5.5 V
- Embedded ECC for single-bit error correction^[1]
- 1.0-V data retention
- TTL- compatible inputs and outputs
- Error indication (ERR) pin to indicate 1-bit error detection and correction
- Available in Pb-free 44-pin TSOP II, 44-SOJ and 48-ball VFBGA

Functional Description

The CY7S1041G is a high-performance PowerSnooze[™] static RAM organized as 256K words × 16 bits. This device features fast access times (10 ns) and a unique ultra-low power Deep-Sleep mode. With Deep-Sleep mode currents as low as 15 μ A, the CY7S1041G/ CY7S1041GE devices combine the best features of fast and low- power SRAMs in industry-standard package options. The device also features embedded ECC. logic which can detect and correct single-bit errors in the accessed location.

Deep-Sleep input (\overline{DS}) must be deasserted HIGH for normal operating mode.

To perform data writes, assert the Chip Enable (\overline{CE}) and Write Enable (\overline{WE}) inputs LOW, and provide the data and address on device data pins $(I/O_0$ through $I/O_{15})$ and address pins $(A_0$ through $A_{17})$ respectively. The Byte High Enable (\overline{BHE}) and Byte Low Enable (\overline{BLE}) inputs control byte writes, and write data on the corresponding I/O lines to the memory location specified. \overline{BHE} controls I/O_8 through I/O_{15} and \overline{BLE} controls I/O_0 through I/O_7 .

To perform data reads, assert the Chip Enable $(\overline{\text{CE}})$ and Output Enable $(\overline{\text{OE}})$ inputs LOW and provide the required address on the address lines. Read data is accessible on the I/O lines (I/O $_0$ through I/O $_{15}$). You can perform byte accesses by asserting the required byte enable signal (BHE or BLE) to read either the upper byte or the lower byte of data from the specified address location

The device is placed in a low-power Deep-Sleep mode when the Deep-Sleep input (\overline{DS}) is asserted LOW. In this state, the device is disabled for normal operation and is placed in a low power data retention mode. The device can be activated by deasserting the Deep-Sleep input (\overline{DS}) to HIGH.

The CY7S1041G is available in 44-pin TSOP II, 48-ball VFBGA and 44-pin (400-mil) Molded SOJ.

Product Portfolio

					F	Power Di	ssipatio	n	
Product [2]	Range	V _{CC} Range (V)	Speed (ns)	Operati (m	A)	Standb (m	A) currer		
				Typ [3]	Max	Typ [3]	Max	Typ [3]	Max
CY7S1041G(E)18		1.65 V–2.2 V	15	_	40	6	8	_	15
CY7S1041G(E)30	Industrial	2.2 V-3.6 V	10	38	45				
CY7S1041G(E)		4.5–5.5 V	10	38	45				

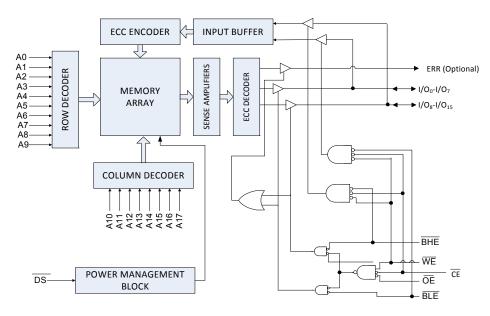
Notes

- 1. This device does not support automatic write back on error detection.
- 2. ERR pin is available only for devices which have ERR option "E" in the ordering code. Refer Ordering Information for details.
- Typical values are included for reference only and are not guaranteed or tested. Typical values are measured at V_{CC} = 1.8 V (for V_{CC} range of 1.65 V 2.2 V), V_{CC} = 3 V (for V_{CC} range of 2.2 V 3.6 V), and V_{CC} = 5 V (for V_{CC} range of 4.5 V 5.5 V), T_A = 25 °C.

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Logic Block Diagram - CY7S1041G / CY7S1041GE





Contents

Pin Configurations	4
Maximum Ratings	6
Operating Range	
DC Electrical Characteristics	
Capacitance	7
Thermal Resistance	7
AC Test Loads and Waveforms	7
Data Retention Characteristics	8
Data Retention Waveform	8
Deep-Sleep Mode Characteristics	9
AC Switching Characteristics	
Switching Waveforms	
Truth Table	
FRR Output - CV7S1041GF	

Ordering information	10
Ordering Code Definitions	16
Package Diagrams	17
Acronyms	20
Document Conventions	20
Units of Measure	20
Document History Page	21
Sales, Solutions, and Legal Information	22
Worldwide Sales and Design Support	
Products	22
PSoC®Solutions	22
Cypress Developer Community	22
Technical Support	



Pin Configurations

Figure 1. 44-pin TSOP II / 44-SOJ pinout, CY7S1041G

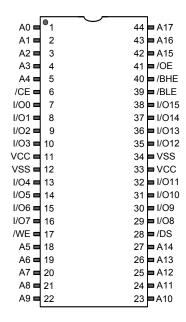


Figure 2. 48-ball VFBGA (6 × 8 × 1.0 mm) pinout, Single Chip Enable without ERR, CY7S1041G $^{[4]}$, Package/Grade ID: BVJXI $^{[6]}$

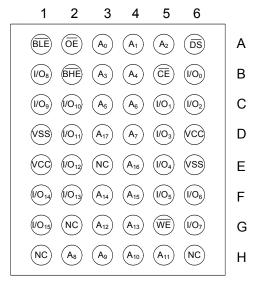
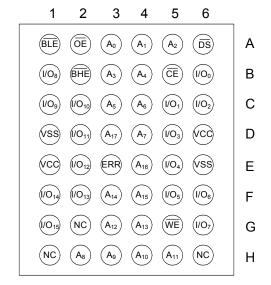


Figure 3. 48-ball VFBGA (6 × 8 × 1.0 mm) pinout, Single Chip Enable with ERR, CY7S1041GE $^{[4,\ 5]}$, Package/Grade ID: BVJXI $^{[6]}$



- 4. NC pins are not connected internally to the die.
- 5. ERR is an output pin.
- Package type BVJXI is JEDEC compliant compared to package type BVXI. The difference between the two is that the higher and lower byte I/Os (I/O_[7:0] and I/O_[15:8] balls are swapped.



Pin Configurations (continued)

Figure 4. 48-ball VFBGA (6 × 8 × 1.0 mm) pinout, Single Chip Enable without ERR, CY7S1041G [7], Package/Grade ID: BVXI [9]

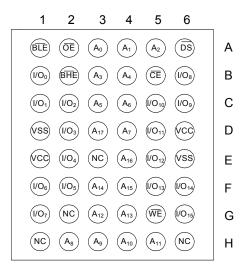


Figure 5. 48-ball VFBGA (6 × 8 × 1.0 mm) pinout, Single Chip Enable with ERR, CY7S1041GE [7, 8], Package/Grade ID: BVXI [9]

1	2	3	4	5	6	
BLE	(ŌĒ)	\bigcirc A ₀	\bigcirc A ₁	\bigcirc A ₂	DS	А
(I/O ₀)	BHE	\bigcirc A ₃	$\bigcirc \!$	$\overline{\overline{\mathbb{CE}}}$	(I/O ₈)	В
(I/O_1)	(I/O ₂)	\bigcirc A ₅	\bigcirc A ₆	(I/O ₁₀)	(I/O ₉)	С
vss	(I/O ₃)	(A ₁₇)	\bigcirc A ₇	(I/O ₁₁)	vcc	D
vcc	(I/O ₄)	ERR	(A ₁₆)	(I/O ₁₂)	vss	E
(I/O ₆)	(I/O ₅)	$\left(A_{14} \right)$	(A ₁₅)	(I/O ₁₃)	(1/O ₁₄)	F
(I/O ₇)	(NC)	$\left(A_{12}\right)$	(A ₁₃)	$\widehat{\overline{\text{WE}}}$	(/O ₁₅)	G
NC	\bigcirc A ₈	$\bigcirc A_9$	(A ₁₀)	$\overbrace{A_{11}}$	NC	Н
	(10°) (10°) (10°) (10°) (10°) (10°) (10°) (10°) (10°)	(10) (10) (10) (10) (10) (10) (10) (10)	(10 ₅ BHE A ₅ (10 ₁ (10 ₂ A ₅ (10 ₃ (10 ₄ ERR (10 ₆ (1	(IO ₀ BHE A ₃ A ₄ (IO ₁ IO ₂ A ₆ A ₆ A ₆ (VSS) (IO ₃ A ₁₇ A ₇ (VCO IO ₄ ERR A ₁₆ (IO ₆ IO ₆ A ₁₄ A ₁₅ (IO ₇ NC A ₁₂ A ₁₃ (A ₁₃ A ₁₅ A ₁₆ (IO ₇ NC A ₁₂ A ₁₃ (IO ₇ IO ₇ IO ₇ (IO ₇ IO ₇ IO ₇ IO ₇ (IO ₇ IO ₇ IO ₇ IO ₇ (IO ₇ IO ₇	(IO ₀ BHE A ₃ A ₄ CE (IO ₁ (IO ₂ A ₅ A ₆ (IO ₁) (VSS) (IO ₃ A ₁₇ A ₇ (IO ₁) (VCO (IO ₄ ERR A ₁₆ (IO ₁) (IO ₆ (IO ₅ A ₁₄ A ₁₅ (IO ₁) (IO ₇ NC A ₁₂ A ₁₃ WE	(IO ₀ BHE A ₅ A ₄ CE IIO ₈ (IO ₁ IIO ₂ A ₅ A ₆ IIO ₁ IIO ₉ (VSS) (IO ₃ A ₁₇ A ₇ IIO ₁ IIO ₉ (VCO IIO ₄ ERR A ₁₆ IIO ₁₂ VSS (IO ₆ IIO ₅ A ₁₄ A ₁₅ IIO ₁₃ IIO ₁₄ (IO ₇ NC A ₁₂ A ₁₃ WE IIO ₁₅

- 7. NC pins are not connected internally to the die.
- 8. ERR is an output pin.
- Package type BVXI is JEDEC compliant compared to package type BVXI. The difference between the two is that the higher and lower byte I/Os (I/O_[7:0] and I/O_[15:8] balls are swapped.



Maximum Ratings

Exceeding maximum ratings may impair the useful life of the device. These user guidelines are not tested.

Storage temperature-65 °C to +150 °C Ambient temperature Supply voltage on V_{CC} relative to GND ^[10]–0.5 V to + 6.0 V

DC voltage applied to outputs

DC input voltage [10]	0.5 V to V _{CC} + 0.5 V
Current into outputs (LOW)	20 mA
Static discharge voltage (MIL-STD-883, Method 3015)	>2001 V
Latch-up current	> 140 mA

Operating Range

Range	Ambient Temperature	V _{CC}
Industrial	–40 °C to +85 °C	1.65 V to 2.2 V, 2.2 V to 3.6 V, 4.5 V to 5.5 V

DC Electrical Characteristics

Over the Operating Range of -40 °C to +85 °C

D	Description		T	•	10 ns / 15 ns			11!4
Parameter	Desc	ription	Test Conditions		Min	Typ [11]	Max	Unit
V _{OH}	Output HIGH	1.65 V to 2.2 V	$V_{\rm CC}$ = Min, $I_{\rm OH}$ = -0.1 m	ıA	1.4	_	_	V
	voltage	2.2 V to 2.7 V	$V_{\rm CC}$ = Min, $I_{\rm OH}$ = -1.0 m	ıA	2	_	_	
		2.7 V to 3.0 V	$V_{\rm CC}$ = Min, $I_{\rm OH}$ = -4.0 m	ıA	2.2	_	_	
		3.0 V to 3.6 V	$V_{\rm CC}$ = Min, $I_{\rm OH}$ = -4.0 m	ıA	2.4	_	_	
		4.5 V to 5.5 V	$V_{\rm CC}$ = Min, $I_{\rm OH}$ = -4.0 m	ıA	2.4	_	_	
		4.5 V to 5.5 V	V_{CC} = Min, I_{OH} = -0.1 m	ıA	$V_{\rm CC} - 0.5^{[13]}$	_	_	
V_{OL}	Output LOW	1.65 V to 2.2 V	V _{CC} = Min, I _{OL} = 0.1 mA		_	_	0.2	V
	voltage	2.2 V to 2.7 V	V _{CC} = Min, I _{OL} = 2 mA		_	_	0.4	
		2.7 V to 3.6 V	V _{CC} = Min, I _{OL} = 8 mA		_	_	0.4	
		3.6 V to 5.5 V	V _{CC} = Min, I _{OL} = 8 mA		_	_	0.4	
	Input HIGH	1.65 V to 2.2 V			1.4	_	V _{CC} + 0.2	V
	voltage	2.2 V to 2.7 V			2	_	V _{CC} + 0.3	
		2.7 V to 3.6 V			2	_	V _{CC} + 0.3	
		3.6 V to 5.5 V			2	_	V _{CC} + 0.5	
V _{IL} ^[10, 12]	Input LOW	1.65 V to 2.2 V			-0.2	_	0.4	V
	voltage	2.2 V to 2.7 V			-0.3	_	0.6	
		2.7 V to 3.6 V			-0.3	_	0.8	
		3.6 V to 5.5 V			-0.5	_	0.8	
I _{IX}	Input leakage c	urrent	$GND \le V_{IN} \le V_{CC}$	$GND \le V_{IN} \le V_{CC}$		_	+1	μΑ
I _{OZ}	Output leakage	current	GND ≤ V _{OUT} ≤ V _{CC} , Out	put disabled	-1	_	+1	μА
I _{CC}		supply current	V _{CC} = Max, I _{OUT} = 0 mA, CMOS levels		_	38	45	mA
		CMOS levels	f = 66.7 MHz	_	40	40		
I _{SB1}	Standby curren	t – TTL inputs	$\begin{aligned} &\text{Max V}_{\text{CC}}, \overline{\text{CE}} \geq \text{V}_{\text{IH}}, \\ &\text{V}_{\text{IN}} \geq \text{V}_{\text{IH}} \text{ or V}_{\text{IN}} \leq \text{V}_{\text{IL}}, \text{ f} \end{aligned}$	= f _{MAX}	_	-	15	mA

^{10.} V_{IL} (min) = -2.0 V and V_{IH} (max) = V_{CC} + 2 V for pulse durations of less than 20 ns.

11. Typical values are included for reference only and are not guaranteed or tested. Typical values are measured at V_{CC} = 1.8 V (for V_{CC} range of 1.65 V – 2.2 V), V_{CC} = 3 V (for V_{CC} range of 2.2V – 3.6 V), and V_{CC} = 5 V (for V_{CC} range of 4.5 V – 5.5 V), T_A = 25 °C.

^{12.} For the \overline{DS} pin, V_{IH} (min) is V_{CC} – 0.2 V and V_{IL} (max) is 0.2 V.

^{13.} This parameter is guaranteed by design and not tested.



DC Electrical Characteristics (continued)

Over the Operating Range of -40 °C to +85 °C

Parameter	Description	Test Conditions	10 ns / 15 ns			Unit
	description Description	rest conditions	Min	Max	Unit	
I _{SB2}	Standby current – CMOS inputs	Max V _{CC} , $\overline{CE} \ge V_{CC} - 0.2 \text{ V}$, DS ≥ V _{CC} - 0.2 V, V _{IN} ≥ V _{CC} - 0.2 V or V _{IN} ≤ 0.2 V, f = 0	-	6	8	mA
I _{DS}	Deep-Sleep current	$\begin{aligned} &\text{Max V}_{\text{CC}}, \overline{\text{CE}} \geq \text{V}_{\text{CC}} - 0.2 \text{ V}, \overline{\text{DS}} \leq 0.2 \text{ V}, \\ &\text{V}_{\text{IN}} \geq \text{V}_{\text{CC}} - 0.2 \text{ V or V}_{\text{IN}} \leq 0.2 \text{ V}, \text{f} = 0 \end{aligned}$	_	_	15	μΑ

Capacitance

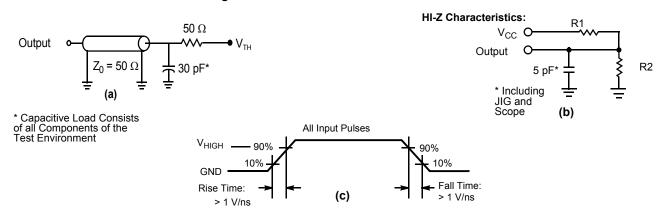
Parameter [14]	Description	Test Conditions	All packages	Unit
C _{IN}	Input capacitance	$T_A = 25 ^{\circ}\text{C}$, $f = 1 \text{MHz}$, $V_{CC(typ)}$	10	pF
C _{OUT}	I/O capacitance		10	pF

Thermal Resistance

Parameter [14]	Description	Test Conditions	48-ball VFBGA	44-pin SOJ	44-pin TSOP II	Unit
U/A	(junction to ambient)	Still air, soldered on a 3 × 4.5 inch, four-layer		55.37	68.85	°C/W
- 30	Thermal resistance (junction to case)	printed circuit board	14.74	30.41	15.97	°C/W

AC Test Loads and Waveforms

Figure 6. AC Test Loads and Waveforms [15]



Parameters	1.8 V	3.0 V	5.0 V	Unit
R1	1667	317	317	Ω
R2	1538	351	351	Ω
V _{TH}	V _{CC} /2	1.5	1.5	V
V_{HIGH}	1.8	3.0	3.0	V

^{14.} Tested initially and after any design or process changes that may affect these parameters.

^{15.} Full-device AC operation assumes a 100- μ s ramp time from 0 to $V_{CC(min)}$ or 100- μ s wait time after V_{CC} stabilization.



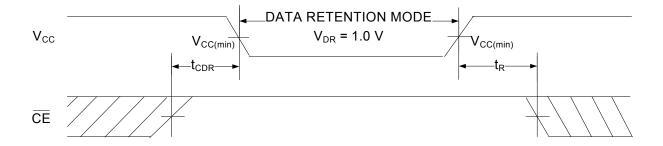
Data Retention Characteristics

Over the Operating Range of -40 °C to +85 °C

Parameter	Description	Conditions ^[16]	Min	Max	Unit
V_{DR}	V _{CC} for data retention		1.0	-	V
I _{CCDR}	Data retention current	$\begin{split} &V_{CC} = V_{DR}, \overline{CE} \ge V_{CC} - 0.2 \text{ V}, \overline{DS} \ge V_{CC} - 0.2 \text{ V}, \\ &V_{IN} \ge V_{CC} - 0.2 \text{ V or } V_{IN} \le 0.2 \text{ V} \end{split}$	-	8	mA
t _{CDR} ^[17]	Chip deselect to data retention time		0	-	ns
t _R ^[17, 18]	Operation recovery time	2.2 V < V _{CC} ≤ 5.5 V	10	ı	ns
		V _{CC} ≤ 2.2 V	15	-	ns

Data Retention Waveform

Figure 7. Data Retention Waveform [18]



Notes
16. DS signal must be HIGH during Data Retention Mode.
17. These parameters are guaranteed by design

^{18.} Full-device operation requires linear V_{CC} ramp from V_{DR} to $V_{CC(min)} \ge 100~\mu s$ or stable at $V_{CC(min)} \ge 100~\mu s$.



Deep-Sleep Mode Characteristics

Over the Operating Range of -40 °C to +85 °C

Parameter	Description	Conditions	Min	Max	Unit
I _{DS}	Deep-Sleep mode current	$V_{CC} = V_{CC} \text{ (max)}, \overline{DS} \le 0.2 \text{ V},$ $V_{IN} \ge V_{CC} - 0.2 \text{ V or } V_{IN} \le 0.2 \text{ V}$	_	15	μA
t _{PDS} ^[19]	Minimum time for $\overline{\text{DS}}$ to be LOW for part to successfully exit Deep-Sleep mode		100	-	ns
t _{DS} ^[20]	DS assertion to Deep-Sleep mode transition time		_	1	ms
t _{DSCD} ^[19]	DS deassertion to chip disable	If $t_{PDS} \ge t_{PDS(min)}$	_	100	μS
		If t _{PDS} < t _{PDS(min)}	_	0	μS
t _{DSCA}	DS deassertion to chip access	If $t_{PDS} \ge t_{PDS(min)}$	300	-	μS
	(Active/Standby)	If t _{PDS} < t _{PDS(min)}			

Chip Allowed Not Allowed Access Allowed ENABLE/ ENABLE/ CE DON'T CARE DISABLE DISABLE DISABLE t_{PDS} DS t_{DS} t_{DSCD} $t_{\text{DSCA}} \\$ Active/Standby Active/Standby Standby Standby Mode Deep Sleep Mode Mode Mode Mode Mode

Figure 8. Active, Standby, and Deep-Sleep Operation Modes

Note

^{19.} $\overline{\text{CE}}$ must be pulled HIGH within t_{DSCD} time of $\overline{\text{DS}}$ deassertion to avoid SRAM data loss.

^{20.} After assertion of $\overline{\text{DS}}$ signal, device will take a maximum of t_{DS} time to stabilize to Deep-Sleep current I_{DS} . During this period, $\overline{\text{DS}}$ signal must continue to be asserted to logic level LOW to keep the device in Deep-Sleep mode.



AC Switching Characteristics

Over the Operating Range of -40 °C to +85 °C

211	D	10	ns	15	11!4	
Parameter [21]	Description	Min	Max	Min	Max	Unit
Read Cycle				•	•	
t _{RC}	Read cycle time	10	_	15	_	ns
t _{AA}	Address to data valid	_	10	_	15	ns
t _{OHA}	Data hold from address change	3	_	3	_	ns
t _{ACE}	CE LOW to data valid	_	10	_	15	ns
t _{DOE}	OE LOW to data valid	_	4.5	_	8	ns
t _{LZOE}	OE LOW to low impedance [22, 23, 24]	0	_	0	_	ns
t _{HZOE}	OE HIGH to HI-Z [22, 23, 24]	_	5	_	8	ns
t _{LZCE}	CE LOW to low impedance [22, 23, 24]	3	_	3	_	ns
t _{HZCE}	CE HIGH to HI-Z [22, 23, 24]	_	5	_	8	ns
t _{PU}	CE LOW to power-up [24]	0	_	0	_	ns
t _{PD}	CE HIGH to power-down [24]	_	10	_	15	ns
t _{DBE}	Byte enable to data valid	_	4.5	_	8	ns
t _{LZBE}	Byte enable to low impedance [22, 23, 24]	0	_	0	_	ns
t _{HZBE}	Byte disable to HI-Z [22, 23, 24]	_	6	_	8	ns
Write Cycle [25	, 26]	•				
t _{WC}	Write cycle time		_	15	_	ns
t _{SCE}	CE LOW to write end	7	-	12	_	ns
t _{AW}	Address setup to write end	7	-	12	_	ns
t _{HA}	Address hold from write end	0	_	0	_	ns
t _{SA}	Address setup to write start	0	-	0	_	ns
t _{PWE}	WE pulse width	7	_	12	_	ns
t _{SD}	Data setup to write end	5	_	8	_	ns
t _{HD}	Data hold from write end	0	_	0	_	ns
t _{LZWE}	WE HIGH to low impedance [22, 23, 24]	3	_	3	_	ns
t _{HZWE}	WE LOW to HI-Z [22, 23, 24]	_	5	_	8	ns
t _{BW}	Byte Enable to End of Write	7	_	12	_	ns

- 21. Test conditions assume a signal transition time (rise/fall) of 3 ns or less, timing reference levels of 1.5 V (for $V_{CC} \ge 3$ V) and $V_{CC}/2$ (for $V_{CC} < 3$ V), and input pulse levels of 0 to 3 V (for $V_{CC} \ge 3$ V) and 0 to V_{CC} (for $V_{CC} < 3$ V). Test conditions for the read cycle use output loading shown in part (a) of Figure 6 on page 7, unless specified otherwise.
- 22. t_{HZOE}, t_{HZCE}, t_{HZWE}, t_{HZBE}, t_{LZOE}, t_{LZOE}, t_{LZOE}, are specified with a load capacitance of 5 pF as in (b) of Figure 6 on page 7. Transition is measured ±200 mV from steady state voltage.
- 23. At any temperature and voltage condition, t_{HZCE} is less than t_{LZCE} , t_{HZBE} is less than t_{LZOE} , t_{HZDE} is less than t_{LZOE} , and t_{HZWE} is less than t_{LZWE} for any device.
- 24. These parameters are guaranteed by design
- 25. The internal write time of the memory is defined by the overlap of $\overline{WE} = V_{IL}$, $\overline{CE} = V_{IL}$, $\overline{DS} = V_{IH}$ and \overline{BHE} or $\overline{BLE} = V_{IL}$. \overline{WE} , \overline{CE} , \overline{BHE} and \overline{BLE} signals must be LOW and \overline{DS} must be HIGH to initiate a write, and a HIGH transition of any of \overline{WE} , \overline{CE} , \overline{BHE} and \overline{BLE} signals or LOW transition on \overline{DS} signal can terminate the operation. The input data setup and hold timing should be referenced to the edge of the signal that terminates the write.
- 26. The minimum write pulse width for Write Cycle No. 2 ($\overline{\text{WE}}$ Controlled, $\overline{\text{OE}}$ LOW) should be the sum of t_{HZWE} and t_{SD} .



Switching Waveforms

Figure 9. Read Cycle No. 1 of CY7S1041G (Address Transition Controlled) [27, 28, 29]

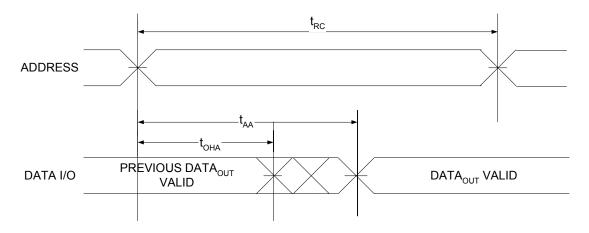
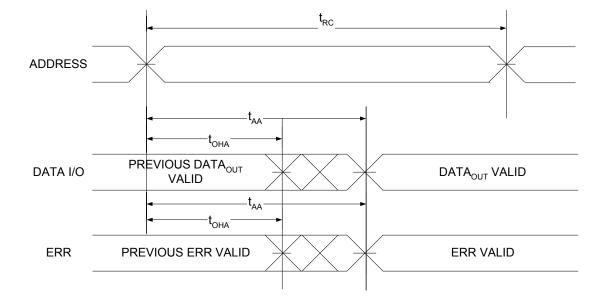


Figure 10. Read Cycle No. 2 of CY7S1041GE (Address Transition Controlled) $^{[27,\,28,\,29]}$

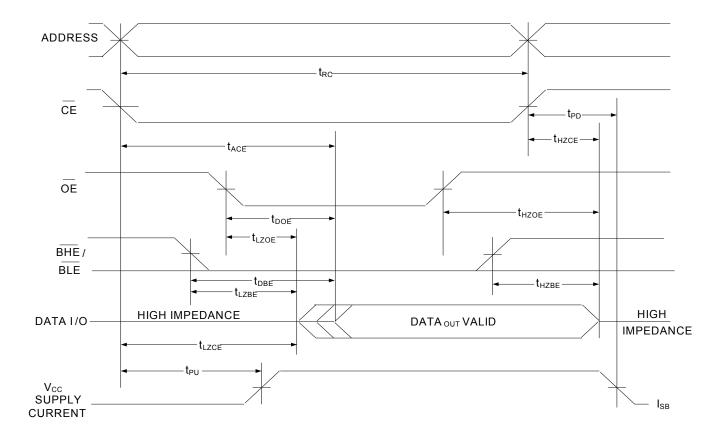


^{27.} The device is continuously selected. \overline{OE} = $V_{|L}$, \overline{CE} = $V_{|L}$, \overline{BHE} or \overline{BLE} or both = $V_{|L}$. 28. \overline{WE} is HIGH for read cycle. 29. \overline{DS} is HIGH for chip access.



Switching Waveforms (continued)

Figure 11. Read Cycle No. 3 ($\overline{\text{OE}}$ Controlled) $^{[30,\ 31,\ 32]}$



Notes_ 30. WE is HIGH for read cycle.

32. DS must be HIGH for chip access

^{31.} Address valid prior to or coincident with $\overline{\text{CE}}$ LOW transition.



Switching Waveforms (continued)

ADDRESS

CE

t_{sa}

t_{sa}

t_{sce}

t_{ha}

t_{ha}

t_{bwe}

Figure 12. Write Cycle No. 1 ($\overline{\text{CE}}$ Controlled) $^{[33,\ 34,\ 35]}$

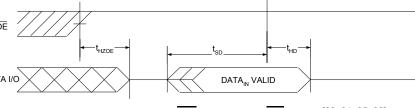
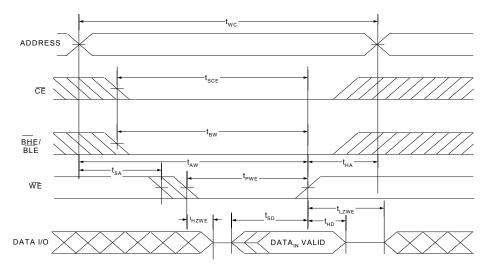


Figure 13. Write Cycle No. 2 ($\overline{\text{WE}}$ Controlled, $\overline{\text{OE}}$ LOW) $^{[33,\ 34,\ 35,\ 36]}$



^{33.} The internal write time of the memory is defined by the overlap of WE = V_{IL}, CE = V_{IL}, DS = V_{IH} and BHE or BLE = V_{IL}. WE, CE, BHE and BLE signals must be LOW and DS must be HIGH to initiate a write, and a HIGH transition of any of WE, CE, BHE and BLE signals or LOW transition on DS signal can terminate the operation. The input data setup and hold timing should be referenced to the edge of the signal that terminates the write.

^{34.} Data I/O is in HI-Z state if $\overline{CE} = V_{IH}$, or $\overline{OE} = V_{IH}$ or \overline{BHE} , and/or $\overline{BLE} = V_{IH}$.

^{35.} DS must be HIGH for chip access.

^{36.} The minimum write pulse width for Write Cycle No. 2 ($\overline{\text{WE}}$ Controlled, $\overline{\text{OE}}$ LOW) should be sum of t_{HZWE} and t_{SD} .



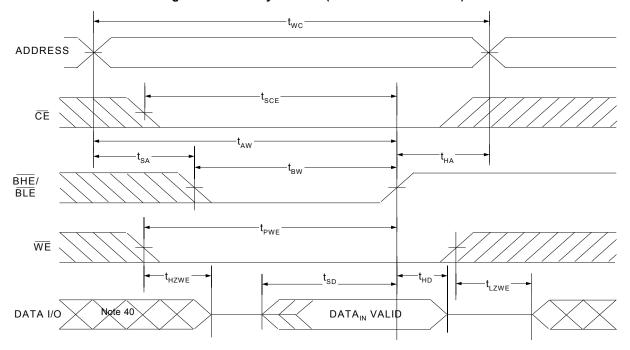
Switching Waveforms (continued)

ADDRESS

CE

The second of the

Figure 15. Write Cycle No. 4 (BLE or BHE Controlled) [37, 38, 39]



- 37. The internal write time of the memory is defined by the overlap of WE = V_{IL}, CE = V_{IL}, DS = V_{IH} and BHE or BLE = V_{IL}. WE, CE, BHE and BLE signals must be LOW and DS must be HIGH to initiate a write, and a HIGH transition of any of WE, CE, BHE and BLE signals or LOW transition on DS signal can terminate the operation. The input data setup and hold timing should be referenced to the edge of the signal that terminates the write.
- 38. \underline{Dat} a I/O is in HI-Z state if $\overline{CE} = V_{IH}$, or $\overline{OE} = V_{IH}$ or $\overline{DS} = V_{IL}$ or \overline{BHE} , and/or $\overline{BLE} = V_{IH}$.
- 39. DS must be HIGH for chip access.
- 40. During this period, the I/Os are in output state. Do not apply input signals.



Truth Table

DS	CE	OE	WE	BLE	BHE	I/O ₀ –I/O ₇	I/O ₈ -I/O ₁₅	Mode	Power
Н	Н	X ^[41]	X ^[41]	X ^[41]	X ^[41]	HIGH-Z	HIGH-Z	Standby	Standby (I _{SB})
Н	L	L	Н	Г	L	Data out	Data out	Read all bits	Active (I _{CC})
Н	L	L	Н	L	Н	Data out	HI-Z	Read lower bits only	Active (I _{CC})
Н	L	L	Н	Н	L	HI-Z	Data out	Read upper bits only	Active (I _{CC})
Н	L	Х	L	L	L	Data in	Data in	Write all bits	Active (I _{CC})
Н	L	Х	L	L	Н	Data in	HI-Z	Write lower bits only	Active (I _{CC})
Н	L	Х	L	Н	L	HI-Z	Data in	Write upper bits only	Active (I _{CC})
Н	L	Н	Н	Х	Х	HI-Z	HI-Z	Selected, outputs disabled	Active (I _{CC})
L ^[42]	Х	Х	Х	Х	Х	HI-Z	HI-Z	Deep-Sleep	Deep-Sleep Ultra Low Power (I _{DS})

ERR Output - CY7S1041GE

Output [43]	ut ^[43] Mode			
0	Read operation, no single-bit error in the stored data.			
1	Read operation, single-bit error detected and corrected.			
HI-Z	Device deselected or outputs disabled or Write operation.			

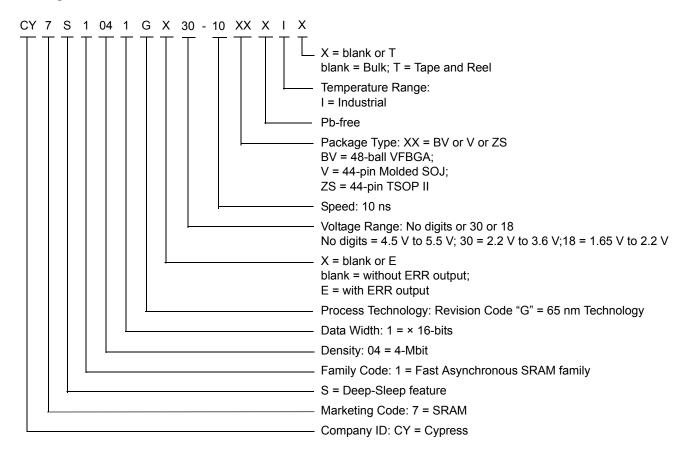
^{41.} The in<u>put</u> voltage levels on these pins should be either at V_{IH} or V_{IL}.
42. V_{IL} on DS must be ≤ 0.2 V.
43. ERR is an Output pin.lf not used, this pin should be left floating.



Ordering Information

Speed (ns)	Voltage Range	Ordering Code	Package Diagram	Package Type (All Pb-free)	Operating Range
10	2.2 V-3.6 V	CY7S1041GE30-10BVXI	51-85150	48-ball VFBGA (6 × 8 × 1.0 mm), ERR output	Industrial
		CY7S1041GE30-10BVXIT	51-85150	48-ball VFBGA (6 \times 8 \times 1.0 mm), ERR output, Tape and Reel	
		CY7S1041G30-10BVXI	51-85150	48-ball VFBGA (6 × 8 × 1.0 mm)	
		CY7S1041G30-10BVXIT	51-85150	48-ball VFBGA (6 × 8 × 1.0 mm), Tape and Reel	
		CY7S1041G30-10VXI	51-85082	44-pin SOJ (400 Mils)	
		CY7S1041G30-10VXIT	51-85082	44-pin SOJ (400 Mils), Tape and Reel	
		CY7S1041G30-10ZSXI	51-85087	44-pin TSOP II	
		CY7S1041G30-10ZSXIT	51-85087	44-pin TSOP II, Tape and Reel	
	4.5 V–5.5 V	CY7S1041G-10ZSXI	51-85087	44-pin TSOP II	
		CY7S1041G-10ZSXIT	51-85087	44-pin TSOP II, Tape and Reel	

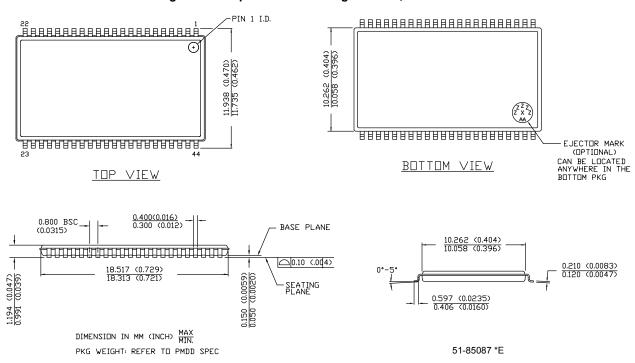
Ordering Code Definitions





Package Diagrams

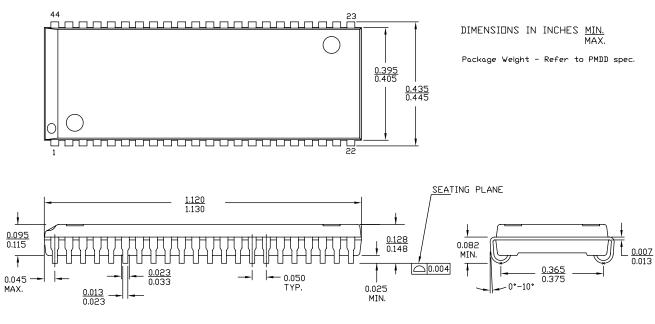
Figure 16. 44-pin TSOP II Package Outline, 51-85087





Package Diagrams (continued)

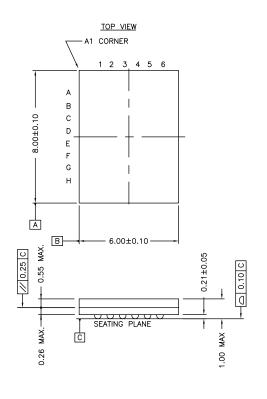
Figure 17. 44-pin SOJ (400 Mils) Package Outline, 51-85082

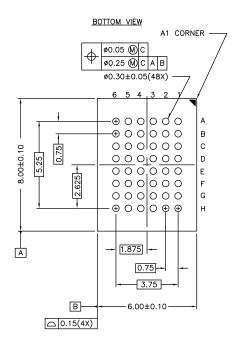




Package Diagrams (continued)

Figure 18. 48-ball VFBGA (6 × 8 × 1.0 mm) BV48/BZ48 Package Outline, 51-85150





NOTE:

51-85150 *H



Acronyms

Acronym	Description			
BHE	Byte High Enable			
BLE	Byte Low Enable			
CE	Chip Enable			
CMOS	Complementary Metal Oxide Semiconductor			
ECC	Error Correcting Code			
I/O	Input/Output			
OE	Output Enable			
SRAM	Static Random Access Memory			
TSOP	Thin Small Outline Package			
TTL	Transistor-Transistor Logic			
VFBGA	Very Fine-Pitch Ball Grid Array			
WE	Write Enable			

Document Conventions

Units of Measure

Symbol	Unit of Measure			
°C	degrees Celsius			
MHz	megahertz			
μΑ	microampere			
μS	microsecond			
mA	milliampere			
mm	millimeter			
ns	nanosecond			
Ω	ohm			
%	percent			
pF	picofarad			
V	volt			
W	watt			



Document History Page

Document Title: CY7S1041G/CY7S1041GE, 4-Mbit (256K words × 16 bit) Static RAM with PowerSnooze™ and Error Correcting Code (ECC)

ECN No.	Orig. of Change	Submission Date	Description of Change
4867081	NILE	07/31/2015	Changed status from Preliminary to Final.
5020880	VINI	11/19/2015	Updated Pin Configurations: Removed 44-pin SOJ package related information. Updated Thermal Resistance: Removed 44-pin SOJ package related information. Added 48-ball VFBGA package related information. Updated Ordering Information: Updated part numbers. Updated Ordering Code Definitions. Updated Package Diagrams: Removed spec 51-85082 *E.
5432554	NILE	09/10/2016	Added 44-pin SOJ package related information in all instances across the document. Updated Logic Block Diagram – CY7S1041G / CY7S1041GE. Updated Maximum Ratings: Updated Note 10 (Replaced "2 ns" with "20 ns"). Updated DC Electrical Characteristics: Removed Operating Range "2.7 V to 3.6 V" and all values corresponding to V _{OH} parameter. Included Operating Ranges "2.7 V to 3.0 V" and "3.0 V to 3.6 V" and all values corresponding to V _{OH} parameter. Changed minimum value of V _{IH} parameter from 2.2 V to 2 V corresponding to Operating Range "3.6 V to 5.5 V". Updated Ordering Information: Updated part numbers. Updated Ordering Code Definitions. Updated Package Diagrams: Added spec 51-85082 *E. Updated to new template. Completing Sunset Review.
	5020880	5020880 VINI 5432554 NILE	5020880 VINI 11/19/2015 5432554 NILE 09/10/2016



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